

Future Missions to Titan: Scientific and Engineering Challenges Low-Temperature Electronics: Opportunities for Titan Science

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KISS, Titan Study, Cal Tech, May 2010

This work was supported by NASA, DTRA, IBM, DARPA, JPL, TI, and NSC.

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Remember ...

There is No Such Thing as Doing Interesting Science on Titan (Physics, Chemistry, Geology Biology, etc.) ...



Without a Robust Electronics Infrastructure!



A Personal Mandate: We Need to Get Rid of That Darn Warm Box!



HOW?!



• **Pro's** for Cooling Electronic Devices and Circuits:

- mobility increases (depends on doping)
- current drive increases
- saturation velocity increases
- latchup in CMOS improves (BJT gain drops)
- thermally-activated failure mechanisms improve (e.g., electromigration)
- subthreshold swing and transconductance improve

• **Con's** for Cooling Electronic Devices and Circuits:

- carrier freeze-out can become an issue (depends on doping)
- breakdown voltages degrade
- hot carrier effects much stronger and can lead to major reliability issues
- heavy ion induced latchup in CMOS looks like a possibility (2010)
- TCAD simulation and compact modeling is a real challenge
- testing is painful
- cycling presents issues for electronic packaging

Technology Options



Assumptions:

- foundry supported (commercially available via MPW)
- low cost
- must support high levels of integration (e.g., mixed-signal SoC)
- can enable robust operation of complex electronics at 93K

Technology Options / Comments:

Bulk Si CMOS

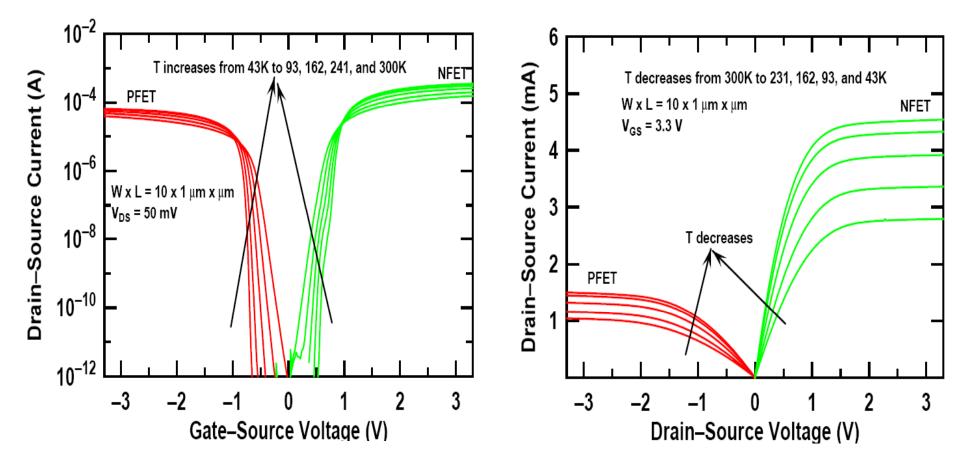
- most performance metrics improve with cooling
- cryo-T hot carrier lifetime is a serious issue to address
- best for digital; okay for analog/RF

Bulk SiGe BiCMOS

- SiGe HBT performance improves with cooling (across board)
- no issue with SiGe HBT cryo-T reliability
- CMOS here has the same pro's/con's as for bulk CMOS
- BiCMOS gives optimal division of labor for analog/RF/digital

Cryo-CMOS Performance Georgia Institute of Technology

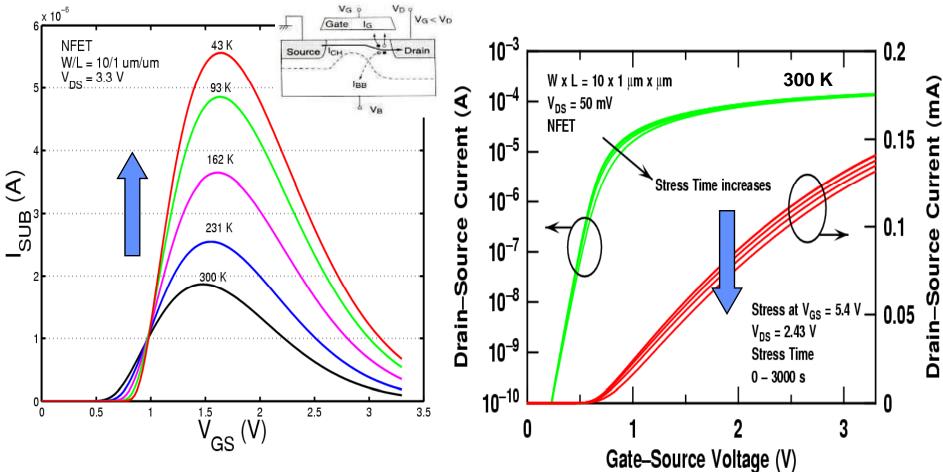
- CMOS Devices Function Well Down to 43 K
- Device Performance Improvement with Cooling (g_m, μ, S)



CMOS Reliability



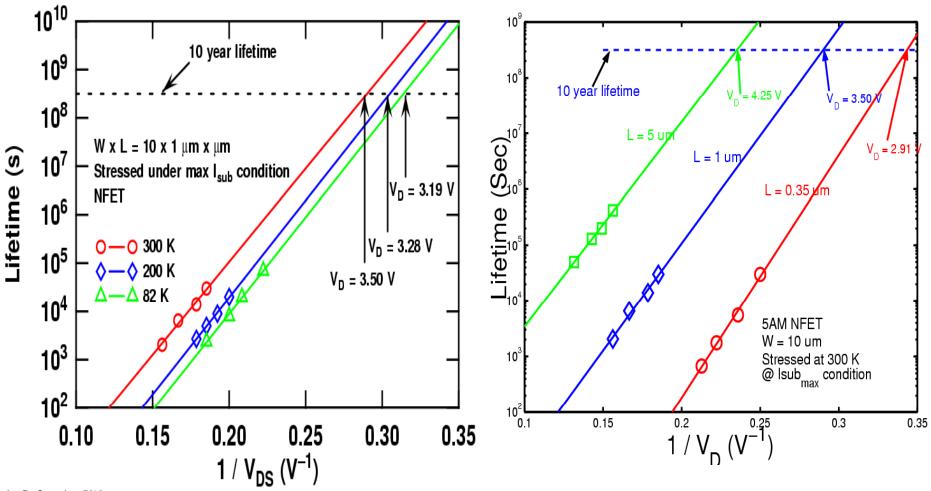
- I_{SUB} is a Good Monitoring Parameter for HCE
- After Stress, I_d and g_m Decrease While V_T and S Increase







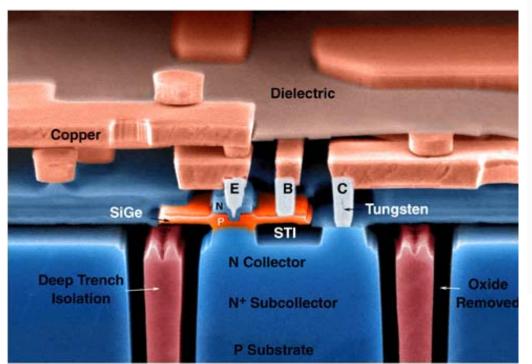
- Lifetime Decreases with Cooling at Fixed L
- Lifetime Decreases With L at Fixed T (Mitigation Path)



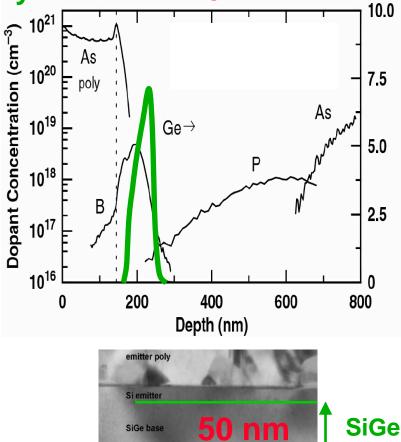
The SiGe HBT



- Conventional Shallow and Deep Trench Isolation + CMOS BEOL
- Unconditionally Stable, SiGe Epitaxial Base Profile
- 100% Si Manufacturing Compatibility
- SiGe HBT + Si CMOS on wafer



SiGe = III-V Speed + Si Manufacturing Win-Win!



Ε

B

Si collector

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Germanium (%)

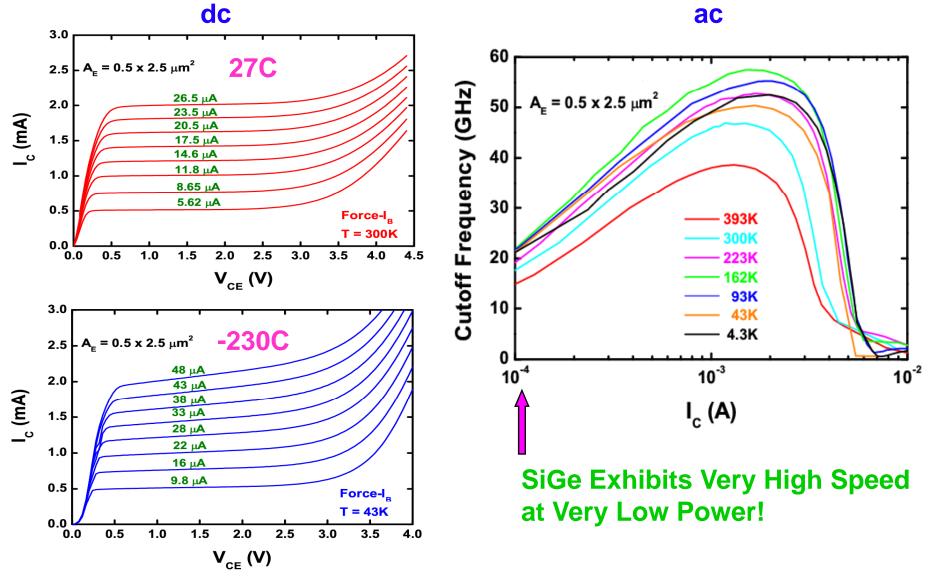
SiGe Performance Limits

- Apparent Convergence of SiGe and III-V on Johnson Curve
- f_T + f_{max} > 1 THz in SiGe Is Clearly Possible (<u>at very modest lith</u>)
 Realistic Goal = BV_{CEO} > 1.5 V @ 500 GHz f_T / f_{max}
- 700 + f_{MAX} = 1 THz - SiGe HB[']Ts ETH SiGe HBTs InP HBTs (300 K 600 - 600 GHz = f_{MAX} , UCSB Proto #3 500 S 4.5 K Σ Peak f^{MAX} 300 K **BV**_{CEO} UIUC Proto #2 1st-3rd gen: (300 K) 200 GHz Proto #1 200 4.5 K 750 GHz-V 100 150 GHz-V Р. 100 200 300 400 500 600 700 100 200 300 500 1000 Peak f₊ (GHz) f_T (GHz)

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SiGe HBTs at Cryo-T



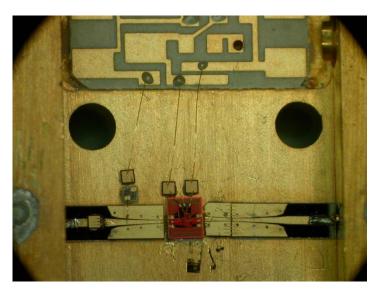


First Generation SiGe HBT

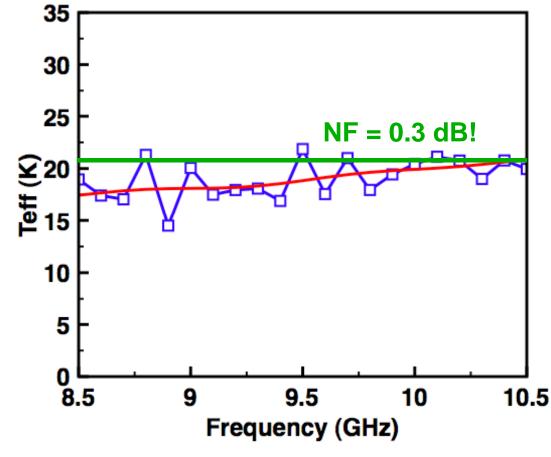


X-band LNA Operation at 15 K (Not Yet Optimized!)

- **T_{eff} < 20 K** (noise T)
- NF < 0.3 dB
- Gain > 20 dB
- *dc* power < 2 mW



Collaboration with S. Weinreb, Cal Tech

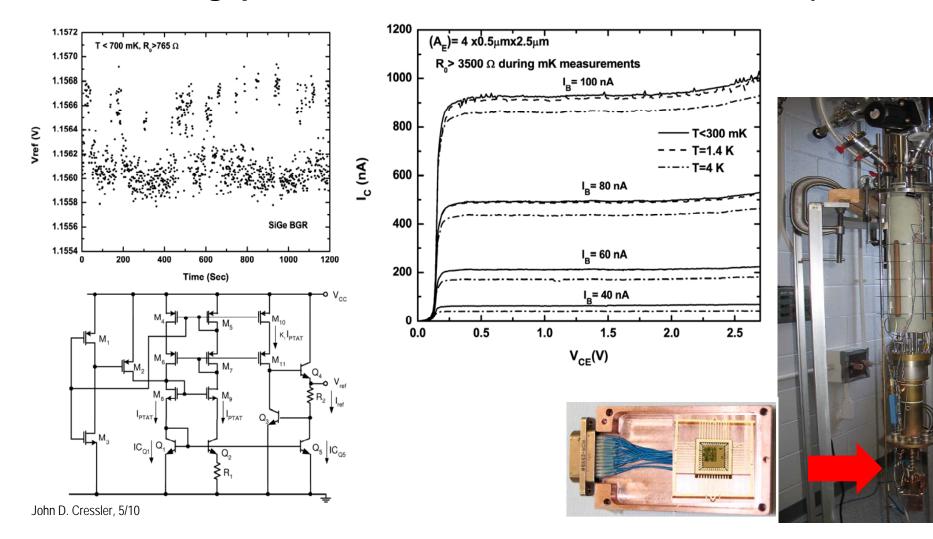


This SiGe LNA is Also Rad-Hard!

Operation at Sub-1K!

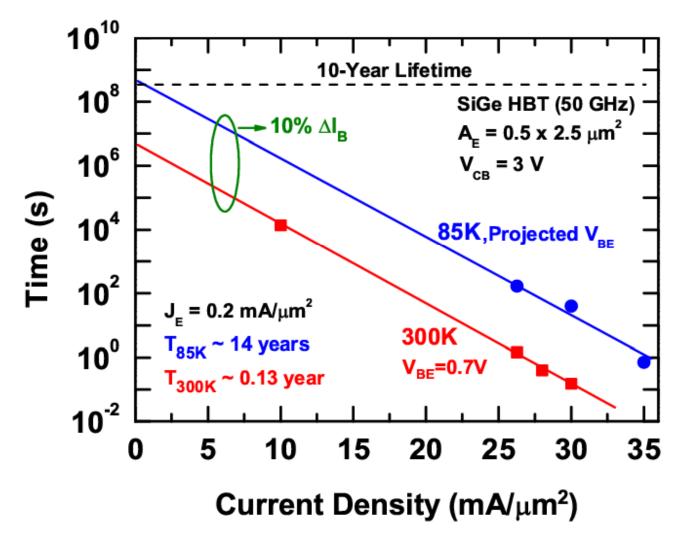


- SiGe HBT Works Just Fine Down to 300 mK!
- SiGe Bandgap Reference Circuit Also Works! (700 mK)





• SiGe HBT Reliability Fine at Cryo-T



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Supports Many Sensor Types:

Temperature, Strain, Pressure, Acceleration, Vibration, Heat Flux, Position, etc.

Use This SiGe REU as a Remote Vehicle Health Monitoring Node

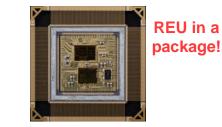
Specifications

- 5" x 3" x 6.75" = 101 in³
- 11 kg
- 17 Watts
- -55°C to +125°C

SiGe Analog

front end die

- Our SWAP Goals 1.5" x 1.5" x 0.5" = 1.1 in³ (100x)
- < 1 kg (10x)
- < 2 Watts (10x)
- -180°C to +125°C, rad tolerant



SiGe Digital

control die

The ETDP SiGe Remote

Electronics Unit. 2010

Georgia Institute of Technology



The X-33

Unit, BAE Systems,

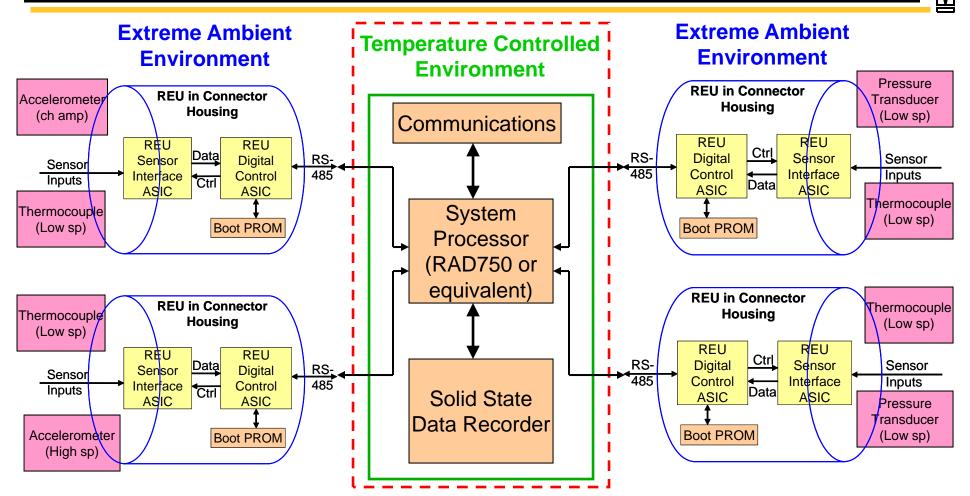
circa 1998

X-33

Remote Health

SiGe REU Architecture

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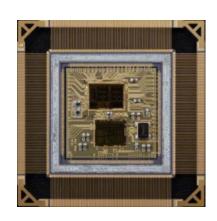


Major Advantages:

- Eliminates Warm Box (size, weight, and power; allows de-centralized architecture)
- Significant Wiring Reduction (weight, reliability, simplifies testing & diagnostics)
- Commonality (easily adapted from one system to the next)



- We now know how to build robust, reliable, complex mixed-signal (analog, digital, RF) electronics to operate at Titan temperatures
- We can provide <u>warm-box free</u> "electronic suites" for a wide class of instrument / sensor / control / comm needs that can provide <u>dramatic</u> reductions in SWAP



Complex On-Surface Electronics analog, digital, RF, power, etc.

- < 1.0 in²
- < 100 g
- < 1-2 W for electronics SYSTEMS

Read: Environmental Invariance (e.g., 90 K)



- Old Idea: one big, heavy, power hungry science package with lots of instruments drops to the surface
- New Idea: identify a "few" (or lots!) target science sensor/instruments (e.g., lab on a chip) that can be packaged at <u>small</u> size and <u>low</u> power and then deploy a "platoon" of such small <u>environmentally invariant</u> science packages by parachute to the surface (land and lake boat with a sail?), each of which have <u>low-power</u> RF links (operating at ambient) for comm from package-to-package or package-to-balloon or package-to-orbiter
- Design small science packages to run off batteries for "long" duration operation, and perhaps even enabled to scavenge energy if desperate (beam RF from orbiter?)